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# NATIONAL STANDARD OF THE

# PEOPLE'S REPUBLIC OF CHINA

# GB/T 14863-1993

## Standard test method for net carrier density in silicon eqitaxial layers by voltage-capacitance of gated and ungated diodes

用栅控和非栅控二极管的电压-电容关系测定硅外延层中净载流子浓度的标准方法

**(English Translation)**

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